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PATENT NUMBER and ISSUE DATE

U.S. UTILÎTY Patent Application

**APPLICANTS: Yoshida Masato; Ashizawa Toranosuke; Terazaki Hiroki; Cotuki Yuui Kurata Yasushi; Matsuzawa Jun; Tanno Kiyohito; **CONTINUING DATA VERIFIED: THIS APPLICATION IS A CON OF 09/581,814 09/08/2000 PAT 6,343,976 * (*) Data inconsistent with PTO records. **FOREIGN APPLICATIONS VERIFIED: JAPAN 09-349240 12/18/1997 JAPAN 10-083042 03/30/1998 JAPAN 10-083043 03/30/1998 PG-PUB DO NOT PUBLISH RESCIND Foreign priority claimed	
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	DISCLAMER	WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.				
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